TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (π-MOSV)

2SK2542

Switching Regulator Applications

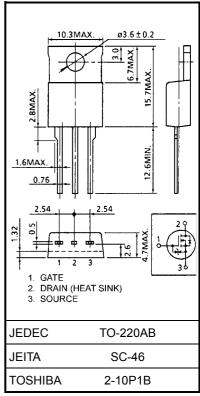
Unit: mm

• 4 V gate drive

 $\begin{array}{ll} \bullet & Low\ drain-source\ ON\ resistance & : R_{DS}\ (ON) = 0.75\ \Omega\ (typ.) \\ \bullet & High\ forward\ transfer\ admittance & : |Y_{fs}| = 7.0\ S\ (typ.) \\ \bullet & Low\ leakage\ current & : I_{DSS} = 100\ \mu A\ (max)\ (V_{DS} = 500\ V) \\ \bullet & Enhancement-mode & : V_{th} = 2.0 \sim 4.0\ V\ (V_{DS} = 10\ V,\ I_{D} = 1\ mA) \end{array}$

Maximum Ratings (Ta = 25°C)

Characteris	stics	Symbol	Rating	Unit	
Drain-source voltage		V_{DSS}	500	V	
Drain-gate voltage (Ro	_{SS} = 20 kΩ)	V_{DGR}	500	V	
Gate-source voltage		V_{GSS}	±30	V	
Drain current	DC (Note 1)	I _D	8	Α	
	Pulse (Note 1)	I _{DP}	32	Α	
Drain power dissipation	n (Tc = 25°C)	P_{D}	80	W	
Single pulse avalanche	e energy (Note 2)	E _{AS}	312	mJ	
Avalanche current		I _{AR}	8	Α	
Repetitive avalanche energy (Note 3)		E _{AR}	8	mJ	
Channel temperature		T _{ch}	150	°C	
Storage temperature range		T _{stg}	-55~150	°C	



Weight: 2.0 g (typ.)

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	1.56	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	83.3	°C/W

Note 1: Please use devices on condition that the channel temperature is below 150°C.

Note 2: V_{DD} = 90 V, T_{ch} = 25°C (initial), L = 8.3 mH, R_G = 25 Ω , I_{AR} = 8 A

Note 3: Repetitive rating: Pulse width limited by maximum channel temperature

This transistor is an electrostatic sensitive device.

Please handle with caution.

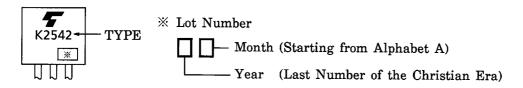
Electrical Characteristics (Ta = 25°C)

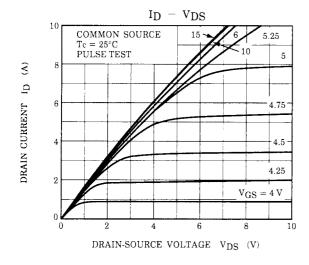
Charac	teristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Gate leakage cu	rrent	I _{GSS}	V _{GS} = ±25 V, V _{DS} = 0 V	_	_	±10	μΑ
Gate-source bre	eakdown voltage	V _(BR) GSS	$I_{G} = \pm 10 \ \mu A, \ V_{GS} = 0 \ V$	±30	-	1	V
Drain cut-off cu	rent	I _{DSS}	V _{DS} = 500 V, V _{DS} = 0 V			100	μA
Drain-source br	eakdown voltage	V _{(BR)DSS}	I _D = 10 mA, V _{GS} = 0 V	500	1	1	V
Gate threshold v	roltage	V_{th}	V _{DS} = 10 V, I _D = 1 mA	2.0		4.0	V
Drain-source O	N resistance	R _{DS (ON)}	V _{GS} = 10 V, I _D = 4 A	1	0.75	0.85	Ω
Forward transfer	admittance	$ Y_{fs} $	V _{DS} = 10 V, I _D = 4 A	3.5	7.0	1	S
Input capacitano	e	C _{iss}		1	1300	1	
Reverse transfer	capacitance	C _{rss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz		130		pF
Output capacitance		Coss		_	400	_	
Switching time	Rise time	t _r	$V_{GS} \stackrel{10 \text{ V}}{\text{O} \text{ V}} \stackrel{\text{I}_{D} = 4 \text{ A}}{\text{O} \text{ V}_{out}}$ $\stackrel{\text{R}_{L}}{\text{E}} = 50 \Omega$ $V_{DD} = 200 \text{ V}$		26	-	
	Turn-on time	t _{on}		ı	45	ı	ne
	Fall time	t _f		-	40	-	ns
	Turn-off time	t _{off}	Duty $\leq 1\%$, $t_{\mathbf{w}} = 10 \mu s$	_	140	_	
Total gate charge (Gate-source plus gate-drain)		Q_{g}		-	30	-	
Gate-source charge		Q_{gs}	$V_{DD} \approx 400 \text{ V}, V_{GS} = 10 \text{ V}, I_D = 8 \text{ A}$		17	_	nC -
Gate-drain ("miller") charge		Q_{gd}			13	_	

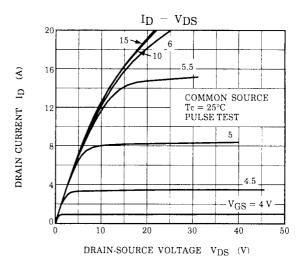
Source-Drain Ratings and Characteristics (Ta = 25°C)

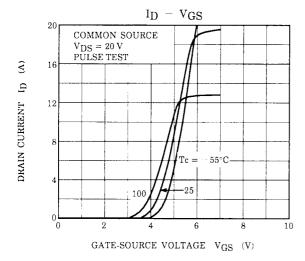
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	_	_	8	Α
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	32	Α
Forward voltage (diode)	V_{DSF}	I _{DR} = 8 A, V _{GS} = 0 V	_	_	-1.7	V
Reverse recovery time	t _{rr}	I _{DR} = 8 A, V _{GS} = 0 V dI _{DR} / dt = 100 A / μs	1	1200		ns
Reverse recovery charge	Q_{rr}	dl _{DR} / dt = 100 A / μs	1	10	1	μC

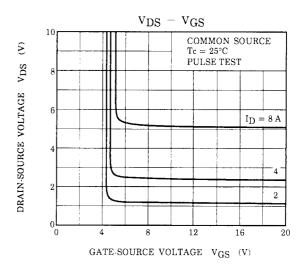
Marking

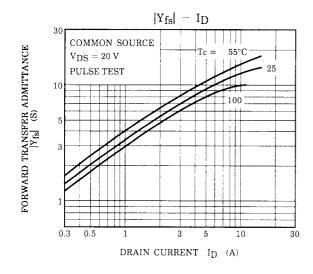


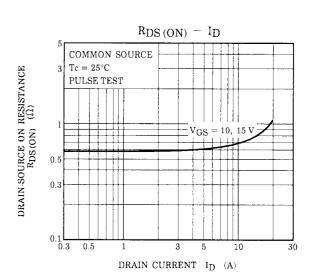




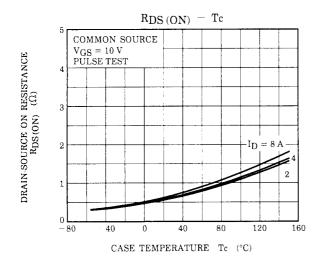


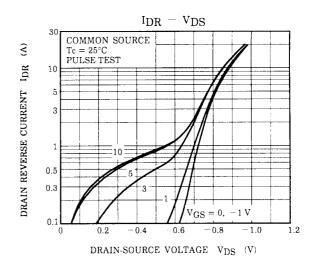


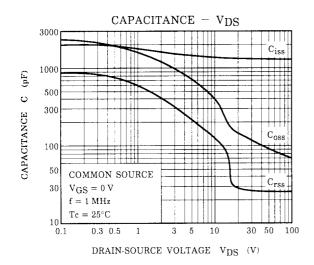


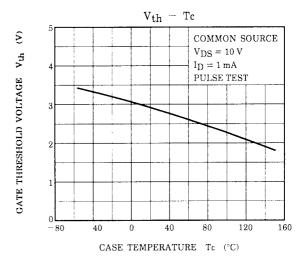


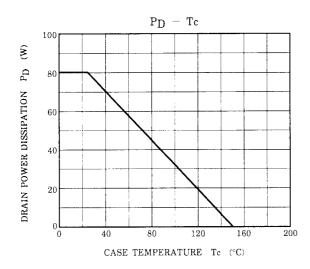
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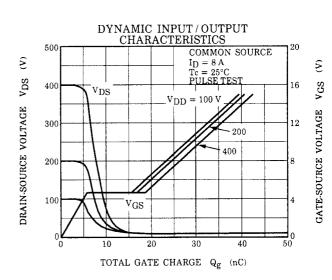




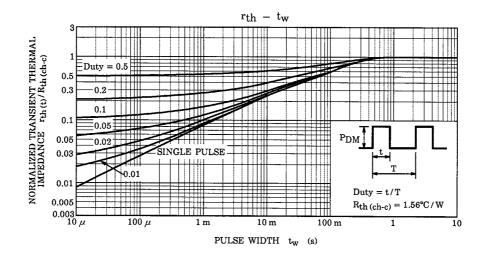


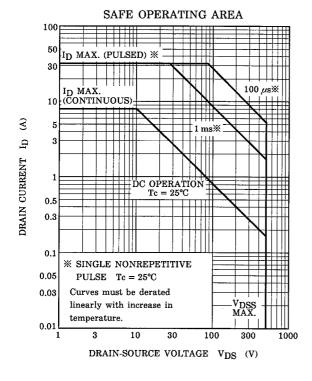


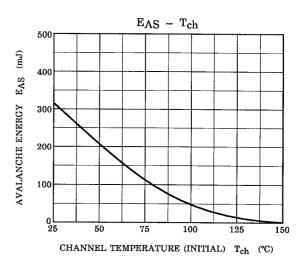


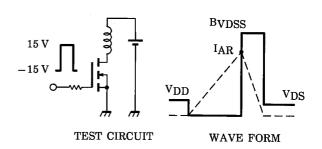


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$$R_G$$
 = 25 Ω
 V_{DD} = 90 V, L = 8.3 mH

$$EAS = \frac{1}{2} \cdot L \cdot I^{2} \cdot \left(\frac{BVDSS}{BVDSS - VDD} \right)$$

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